Keynote

Roger W. Blethen was appointed President and Chief Executive Officer of LTX Corporation in 1996 and is a member of the company’s Board of Directors. LTX, the leader is Semiconductor Test Equipment for testing advanced integrated circuits known as system-on-a-chip (SOC), is headquartered near Boston in Westwood, Massachusetts.

A co-founder of LTX Corporation in 1976, Mr. Blethen has led the development and marketing of three generations of Semiconductor Test Equipment platforms. Each of these systems was an innovation in its time—including the industry’s first mixed-signal test system, digital resource-per-pin tester, and high-speed multi-processing architecture. In 1997, recognizing the IC industry’s emerging emphasis on system-on-a-chip, Mr. Blethen initiated development of LTX’s Fusion HF—a product that is now the leading SOC tester and only single-platform system. By 1999, a new business and financial model had been coupled with Fusion’s selection by six of the top twelve IC producers worldwide, completing his re-launch of LTX Corporation.

Roger Blethen received his Bachelor of Science degree in Electrical Engineering from Northeastern University where he currently serves as a member of their Industrial Advisory Board for the Department of Electrical and Computer Engineering and where he is a charter member of the Legacy Scholarship initiative. Mr. Blethen also serves as an advisor to the U.S. Department of Commerce Technical Advisory Board for export controls. Mr. Blethen is also a member of the California Executive Forum.

Abstract
Semiconductors continue to fly forward with advances in complexity and performance at the same time as they shrink in size and fall in power consumption. How will test engineers add to their company's value proposition and how will test engineering evolve?